



**Arab Academy for Science & Technology
and Maritime Transport – Cairo Branch**
College of Engineering & technology
Electronics & Communication Engineering Department



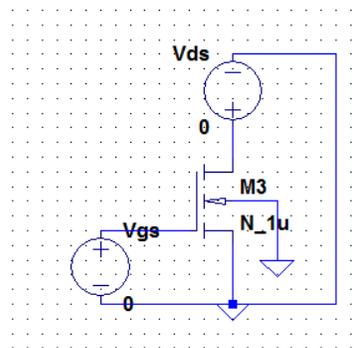
Course: Selected Topics in Electronics

Course Code: EC538

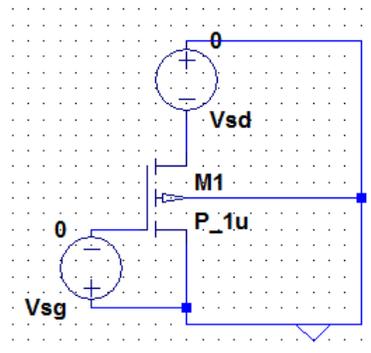
Problem Set

MOSFET I-V Characteristics

P1. Plot the I_d - V_{ds} curve with V_{gs} ranging from 0 to 5 using Level 3 N-MOSFET Model for $L=1\mu$ and $W=10\mu$ in `cmosedu_models.txt`.



P2. Plot the I_d - V_{sd} curve with V_{sg} ranging 0 to 5 using Level 3 P-MOSFET Model for $L=1\mu$ and $W=10\mu$ in `cmosedu_models.txt`.



P3. Plot the I_d - V_{ds} curve with V_{gs} ranging from 0 to 1 using BSIM4 N-MOSFET Model for $L=50\text{n}$ and $W=500\text{n}$ in `cmosedu_models.txt`.

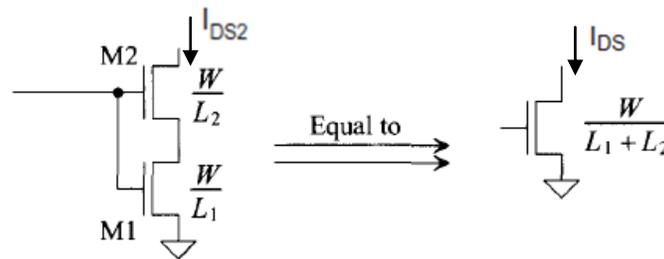
P4. Plot the I_d - V_{sd} curve with V_{sg} ranging 0 to 1 using BSIM4 P-MOSFET Model for $L=50\text{n}$ and $W=500\text{n}$ in `cmosedu_models.txt`.

MOSFET Series/Parallel Configurations

P5. Show that the parallel connection of the MOSFETs shown below behave as a single MOSFET with a width equal to the sum of each individual MOSFET width.

Prove using LTSpice for the Level 3 N-MOSFET Model.

P6. Show that the series connection of MOSFETs shown behaves as a single MOSFET with twice the length of the individual MOSFETs. Neglect the body effect.

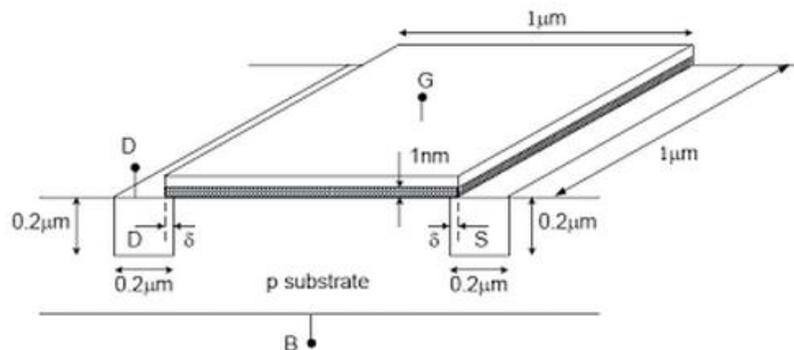


MOSFET Capacitance

P7. A 90 nm long transistor has a gate oxide thickness of 16 Å. What is its gate capacitance per micron of width?

P8. Calculate the diffusion parasitic C_{db} of the drain of a unit-sized contacted NMOS transistor in a 0.6 μm process if the size of the diffusion contact is $4 \times 5\lambda$ when the drain is at 0 and at $V_{DD} = 5\text{ V}$. Assume the substrate is grounded. The transistor characteristics are $C_J = 0.42\text{ fF}/\mu\text{m}^2$, $M_J = 0.44$, $C_{JSW} = 0.33\text{ fF}/\mu\text{m}$, $M_{JSW} = 0.12$, and $\psi_0 = 0.98\text{ V}$ at room temperature.

P9. In the three dimensional view of a silicon n-channel MOS transistor shown below, $\delta = 20\text{ nm}$. The transistor is of width $1\ \mu\text{m}$. The depletion width formed at every p-n junction is 10 nm. The relative permittivity of Si and SiO_2 respectively, are 11.7 and 3.9, and $\epsilon_0 = 8.9 \times 10^{-12}\text{ F/m}$. Find the gate source overlap capacitance.



Body Effect

P10. Using LTSpice, for NMOS and PMOS:

- Find the value of the threshold voltage if $V_{sb}/V_{bs}=0$.
- Prove that when V_{sb}/V_{bs} is increased, the threshold voltage goes up.
- Draw I_d versus V_{sb}/V_{bs} .

Compare all of the above using both Level3 and BSIM4 Model cards.

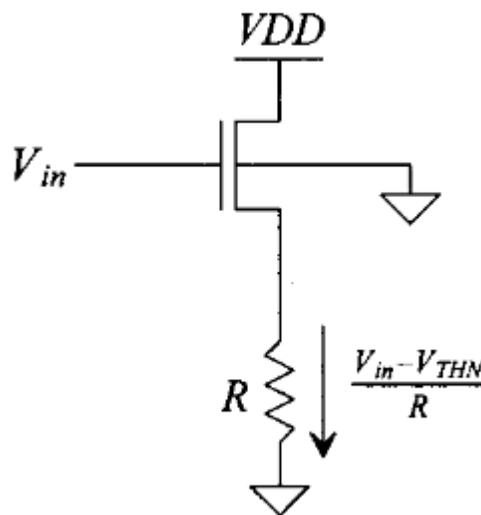
P11. Sometimes the substrate is connected to a voltage called the substrate bias to alter the threshold of the nMOS transistors. If the threshold of an nMOS transistor is to be raised, should a positive or negative substrate bias be used?

P13. Consider the nMOS transistor in a $0.6\ \mu\text{m}$ process with gate oxide thickness of $100\ \text{\AA}$. The doping level is $N_A = 2 \times 10^{17}\ \text{cm}^{-3}$ and the nominal threshold voltage is $0.7\ \text{V}$. The body is tied to ground with a substrate contact. How much does the threshold change at room temperature if the source is at $4\ \text{V}$ instead of 0 ? The intrinsic carrier concentration for Silicon is $1.45 \times 10^{10}\ \text{cm}^{-3}$ and the relative permittivity for Silicon is 11.7 .

P14. For the following voltage to current converter, the resistor value is given as $10\ \text{M}\Omega$ and $V_{DD} = 5\ \text{V}$ is applied. For an input voltage ranging from $1\ \text{V}$ to $5\ \text{V}$:

- Simulate the circuit
- Show that the $I_{\text{out}}-V_{\text{in}}$ simulated is not linear?
- What is the ideal slope for the given circuit?

Use long-channel device.



P15. For an nMOS long channel transistor, simulate a circuit using LT spice that outputs the threshold voltage versus the source to body voltage.